捷多邦,专业PCB打样工 20月7月10日 20

Features

- Fast Read Access Time 90 ns
 - **Dual Voltage Range Operation** Low Voltage Power Supply Range, 3.0V to 3.6V or Standard 5V ± 10% Supply Range
- **Compatible with JEDEC Standard AT27C512**
 - Low Power CMOS Operation 20 μA max. (less than 1 μA typical) Standby for V_{CC} = 3.6V 29 mW max. Active at 5 MHz for V_{CC} = 3.6V
- JEDEC Standard Packages 32-Lead PLCC
 - 28-Lead 330-mil SOIC
 - 28-Lead TSOP
- High Reliability CMOS Technology 2.000V ESD Protection 200 mA Latchup Immunity
- Rapid[™] Programming Algorithm 100 µs/byte (typical)
- CMOS and TTL Compatible Inputs and Outputs
 - JEDEC Standard for LVTTL
- Integrated Product Identification Code
- **Commercial and Industrial Temperature Ranges**

Description

The AT27LV512A is a high performance, low power, low voltage 524,288 bit one-time programmable read only memory (OTP EPROM) organized as 64K by 8 bits. It requires only one supply in the range of 3.0V to 3.6V in normal read mode operation, making it ideal for fast, portable systems using battery power.

Atmel's innovative design techniques provide fast speeds that rival 5V parts while keeping the low power consumption of a 3.3V supply. At V_{CC} = 3.0V, any byte can be accessed in less than 90 ns. With a typical power dissipation of only 18 mW at 5 MHz and $V_{CC} = 3.3V$, the AT27LV512A consumes less than one fifth the power of a standard 5V EPROM. (continued)

Pin Configurations

are DON'T CONNECT.

Pin Name	Function	
A0 - A15	Addresses	A7 G 3 26 A1
00 - <mark>07</mark>	Outputs	A5 🗆 5 24 🗅 A9
CE	Chip Enable	A4 □ 6 23 □ <u>A1</u> A3 □ 7 22 □ OE
OE/V _{PP}	Output Enable	A2 □ 8 21 □ <u>A1</u> A1 □ 9 20 □ CE
NC	No Connect	A0 □ 10 19 □ 07 00 □ 11 18 □ 06
A7 A15	C Top View	01 12 17 0 05 02 13 16 0 04 GND 14 15 03
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	32 30 1 31 29 A8 28 A9	TSOP Top View Type 1
A4 > 7 A3 > 8 A2 > 9	27 〈 A11 26 〈 <u>NC</u> 25 〈 OE/VPP	OE/VPP 22 A11 23 24 A9 A8 25
A1 > 10 A0 > 11 NC > 12	24 (<u>A10</u> 23 (CE 22 (O7	$\begin{array}{c} A13 \\ A14 \\ VCC \\ A15 \\ 1 \end{array} \begin{array}{c} 2^{26} \\ 27 \\ 28 \\ 1 \end{array}$
00 { 13 15 14 16	17 19 21 06 18 20 18 20 18 20 18 20 18 20 18 20 18 20 18 20 18 20 18 20 18 20 18 20 18 20 18 20 18 20 18 20 18 20 18 20 20 20 20 20 20 20 2	A12 12 2 A7 3 A6 4 A5 5
02 01 GN	NC 04 D 03 05	A4 A3 = 7 6
Note: PLCC I	Package Pins 1 and 17	7

512K (64K x 8) Low Voltage **OTP CMOS EPROM**





0607A



SOIC Top View

VCC □ A14 □ A13 27 26 25 □ A8 A9 A11 24 23

21

19

17

15

13

11

9

20

18

16

14

12

10

8

A10

07

O5

О3

02

00

A1

CE

06

O4

01

A0

A2

GND



Description (Continued)

Standby mode supply current is typically less than 1 μA at 3.3V.

The AT27LV512A is available in industry standard JEDEC-approved one-time programmable (OTP) plastic PLCC, SOIC, and TSOP packages. All devices feature two-line control (CE, OE) to give designers the flexibility to prevent bus contention.

The AT27LV512A operating with V_{CC} at 3.0V produces TTL level outputs that are compatible with standard TTL logic devices operating at V_{CC} = 5.0V. The device is also capable of standard 5-volt operation making it ideally suited for dual supply range systems or card products that are pluggable in both 3-volt and 5-volt hosts.

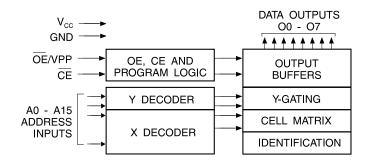
Atmel's AT27LV512A has additional features to ensure high quality and efficient production use. The Rapid[™] Programming Algorithm reduces the time required to program the part and guarantees reliable programming. Programming time is typically only 100 µs/byte. The Integrated Product Identification Code electronically identifies the device and manufacturer. This feature is used by industry standard programming equipment to select the proper programming algorithms and voltages. The AT27LV512A programs exactly the same way as a standard 5V AT27C512R and uses the same programming equipment.

System Considerations

Switching between active and standby conditions via the Chip Enable pin may produce transient voltage excursions. Unless accommodated by the system design, these transients may exceed data sheet limits, resulting in device non-conformance. At a minimum, a 0.1 μ F high frequency, low inherent inductance, ceramic capacitor should be utilized for each device. This capacitor should be connected between the V_{CC} and Ground terminals of the device, as close to the device as possible. Additionally, to stabilize the supply voltage level on printed circuit boards with large EPROM arrays, a 4.7 μ F bulk electrolytic capacitor should be utilized, again connected between the V_{CC} and Ground terminals. This capacitor should be positioned as close as possible to the point where the power supply is connected to the array.

AT27LV512A

Block Diagram



Absolute Maximum Ratings*

Temperature Under Bias40°C to +85°C
Storage Temperature65°C to +125°C
Voltage on Any Pin with Respect to Ground2.0V to +7.0V ⁽¹⁾
Voltage on A9 with Respect to Ground2.0V to +14.0V $^{(1)}$
VPP Supply Voltage with Respect to Ground2.0V to +14.0V ⁽¹⁾

*NOTICE: Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

Note: 1. Minimum voltage is -0.6V dc which may undershoot to -2.0V for pulses of less than 20 ns. Maximum output pin voltage is V_{CC} + 0.75V dc which may be exceeded if certain precautions are observed (consult application notes) and which may overshoot to +7.0 volts for pulses of less than 20 ns.

Operating Modes

Mode \ Pin \overline{CE} \overline{OE}/V_{PP}		Ai	V _{CC}	Outputs	
Read ⁽²⁾	VIL	VIL	Ai	Vcc ⁽²⁾	Dout
Output Disable (2)	VIL	Vih	X ⁽¹⁾	Vcc ⁽²⁾	High Z
Standby ⁽²⁾	VIH	Х	Х	V _{CC} ⁽²⁾	High Z
Rapid Program ⁽³⁾	VIL	VPP	Ai	V _{CC} ⁽³⁾	D _{IN}
PGM Inhibit ⁽³⁾	VIH	Vpp	Х	Vcc ⁽³⁾	High Z
Product Identification ^(3, 5)	VIL	VIL	$\begin{array}{l} A9 = V_{H}^{(4)} \\ A0 = V_{IH} \text{ or } V_{IL} \\ A1 - A15 = V_{IL} \end{array}$	Vcc ⁽³⁾	Identification Code

Notes: 1. X can be V_{IL} or V_{IH} .

2. Read, output disable, and standby modes require, $3.0V \le V_{CC} \le 3.6V$, or $4.5V \le V_{CC} \le 5.5V$.

Refer to Programming Characteristics. Programming modes require V_{CC} = 6.5V.

4. $V_H = 12.0 \pm 0.5 V$.

5. Two identifier bytes may be selected. All Ai inputs are held low (V_{IL}), except A9 which is set to V_H and A0 which is toggled low (V_{IL}) to select the Manufacturer's Identification byte and high (V_{IH}) to select the Device Code byte.





DC and AC Operating Conditions for Read Operation

			AT27LV512A	
		-90	-12	-15
Operating Temperature	Com.	0°C - 70°C	0°C - 70°C	0°C - 70°C
(Case)	Ind.	-40°C - 85°C	-40°C - 85°C	-40°C - 85°C
Vee Dower Supply		3.0V to 3.6V	3.0V to 3.6V	3.0V to 3.6V
V _{CC} Power Supply		5V ± 10%	5V ± 10%	5V ± 10%

DC and Operating Characteristics for Read Operation

Symbol	Parameter	Condition	Min	Max	Units
$V_{CC} = 3$.0V to 3.6V				
ILI	Input Load Current	VIN = 0V to VCC		±1	μA
Ilo	Output Leakage Current	Vout = 0V to Vcc		±5	μA
I _{PP1} ⁽²⁾	VPP (1) Read/Standby Current	$V_{PP} = V_{CC}$		10	μA
I _{SB}	V _{CC} ⁽¹⁾ Standby Current	Isb1 (CMOS), $\overline{CE} = V_{CC} \pm 0.3V$		20	μA
128		I_{SB2} (TTL), $\overline{CE} = 2.0$ to $V_{CC} + 0.5V$		100	μA
ICC	V _{CC} Active Current	$\frac{f = 5 \text{ MHz, } I_{OUT} = 0 \text{ mA,}}{CE} = V_{IL}$		8	mA
VIL	Input Low Voltage		-0.6	0.8	V
VIH	Input High Voltage		2.0	Vcc + 0 .5	V
Vol	Output Low Voltage	I _{OL} = 2.0 mA		0.4	V
Vон	Output High Voltage	I _{OH} = -2.0 mA	2.4		V
$V_{CC} = 4$.5V to 5.5V				
ILI	Input Load Current	VIN = 0V to VCC		±1	μA
ILO	Output Leakage Current	$V_{OUT} = 0V$ to V_{CC}		±5	μA
I _{PP1} ⁽²⁾	VPP ⁽¹⁾ Read/Standby Current	$V_{PP} = V_{CC}$		10	μA
	V _{CC} ⁽¹⁾ Standby Current	I _{SB1} (CMOS), $\overline{CE} = V_{CC} \pm 0.3V$		100	μA
I _{SB}		I_{SB2} (TTL), \overline{CE} = 2.0 to V _{CC} + 0.5V		1	mA
Icc	V _{CC} Active Current	$\frac{f = 5 \text{ MHz}, I_{OUT} = 0 \text{ mA},}{CE = V_{IL}}$		20	mA
VIL	Input Low Voltage		-0.6	0.8	V
VIH	Input High Voltage		2.0	V _{CC} + 0.5	V
Vol	Output Low Voltage	lo _L = 2.1 mA		0.4	V
Vон	Output High Voltage	Іон = -400 μА	2.4		V

Note: 1. V_{CC} must be applied simultaneously with or before \overline{OE}/V_{PP} , and removed simultaneously with or after \overline{OE}/V_{PP} .

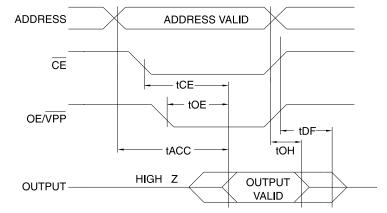
AT27LV512A

AC Characteristics for Read Operation ($V_{CC} = 3.0V$ to 3.6V and 4.5V to 5.5V)

			-!	90	-	12	-*	15	
Symbol	Parameter	Condition	Min	Max	Min	Max	Min	Max	Units
t _{ACC} ⁽³⁾	Address to Output Delay $\overline{CE} = \overline{OE}/V_{PP} = V_{IL}$			90		120		150	ns
tce (2)	\overline{CE} to Output Delay $\overline{OE}/V_{PP} = V_{IL}$			90		120		150	ns
toe ^(2, 3)	\overline{OE}/V_{PP} to Output Delay $\overline{CE} = V_{IL}$			50		50		60	ns
t _{DF} ^(4, 5)	OE/VPP or CE High to Output Float, whichever occurred first			40		40		50	ns
tон	Output Hold from Address, CE or OE/VPP, whichever occurred first		0		0		0		ns

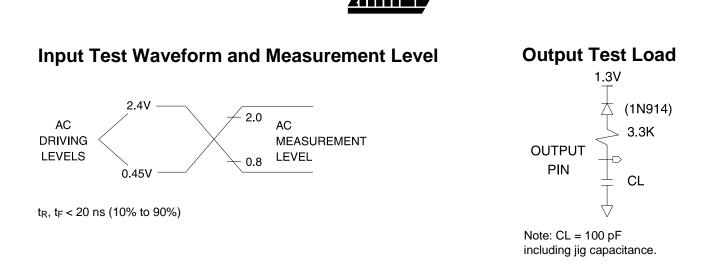
Notes: 2, 3, 4, 5. - see AC Waveforms for Read Operation.

AC Waveforms for Read Operation ⁽¹⁾



- Notes: 1. Timing measurement references are 0.8V and 2.0V. Input AC drive levels are 0.45V and 2.4V, unless otherwise specified.
 - OE/V_{PP} may be delayed up to t_{CE} t_{OE} after the falling edge of CE without impact on t_{CE}.
 - 3. OE/V_{PP} may be delayed up to t_{ACC} t_{OE} after the address is valid without impact on t_{ACC}.
- 4. This parameter is only sampled and is not 100% tested.
- 5. Output float is defined as the point when data is no longer driven.

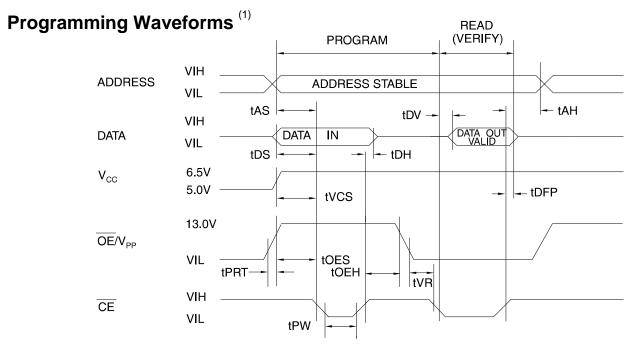




Pin Capacitance (f = 1 MHz, T = 25° C)⁽¹⁾

	Тур	Max	Units	Conditions
CIN	4	6	pF	$V_{IN} = 0V$
Соит	8	12	pF	$V_{OUT} = 0V$

Note: 1. Typical values for nominal supply voltage. This parameter is only sampled and is not 100% tested.



Notes: 1. The Input Timing Reference is 0.8V for VIL and 2.0V for VIH.

2. toE and tDFP are characteristics of the device but must be accommodated by the programmer.

DC Programming Characteristics

 T_{A} = 25 $\pm~$ 5°C, V_{CC} = 6.5 $\pm~$ 0.25V, $\overline{\text{OE}}/\text{V}_{\text{PP}}$ = 13.0 $\pm~$ 0.25V

			L		
Symbol	Parameter	Test Conditions	Min	Max	Units
ILI	Input Load Current	$V_{IN} = V_{IL}, V_{IH}$		10	μA
VIL	Input Low Level		-0.6	0.8	V
Vih	Input High Level		2.0	V _{CC} + 0.5	V
Vol	Output Low Voltage	I _{OL} = 2.1 mA		0.4	V
Voн	Output High Voltage	I _{OH} = -400 μA	2.4		V
ICC2	V _{CC} Supply Current (Program and Verify)			25	mA
I _{PP2}	OE/VPP Current	$\overline{CE} = V_{IL}$		25	mA
VID	A9 Product Identification Voltage		11.5	12.5	V





AC Programming Characteristics

 $T_A = 25 \pm 5^{\circ}C, V_{CC} = 6.5 \pm 0.25V, \overline{OE}/V_{PP} = 13.0 \pm 0.25V$

Sym- bol	Test Conditions* ⁽¹⁾ Parameter	Liı Min	nits Max	Units
tAS	Address Setup Time	2		μS
toes	OE/V _{PP} Setup Time	2		μS
toeh	OE/VPP Hold Time	2		μS
tDS	Data Setup Time	2		μS
tан	Address Hold Time	0		μS
tDH	Data Hold Time	2		μS
tDFP	CE High to Output Float Delay ⁽²⁾	0	130	ns
tvcs	V _{CC} Setup Time	2		μS
tpw	CE Program Pulse Width (3)	95	105	μS
t _{DV}	Data Valid from $\overline{CE}^{(2)}$		1	μS
t∨R	OE/VPP Recovery Time	2		μS
tPRT	OE/V _{PP} Pulse Rise Time During Programming	50		ns

*AC Conditions of Test:

Input Rise and Fall Times (10% to 90%)......20 ns Input Pulse Levels.....0.45V to 2.4V Input Timing Reference Level.....0.8V to 2.0V Output Timing Reference Level.....0.8V to 2.0V

- Notes: 1. $\frac{V_{CC}}{OE}$ must be applied simultaneously or before $\frac{OE}{OE}/V_{PP}$ and removed simultaneously or after OE/V_{PP} .
 - 2. This parameter is only sampled and is not 100% tested. Output Float is defined as the point where data is no longer driven —see timing diagram.
 - 3. Program Pulse width tolerance is 100 $\mu sec \pm 5\%.$

Atmel's 27LV512A Integrated Product Identification Code ⁽¹⁾

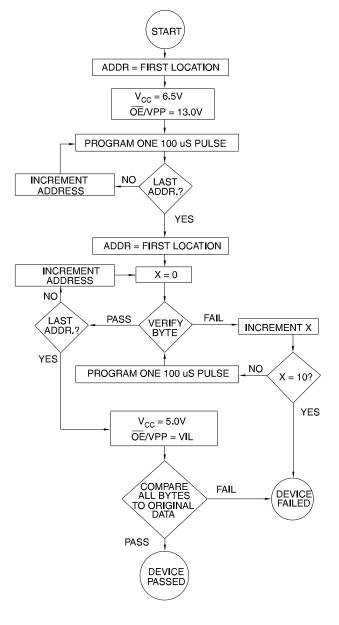
					Pins	5				Hex
Codes	A0	07	O6	O5	O4	O3	O2	01	O 0	Data
Manufacturer	0	0	0	0	1	1	1	1	0	1E
Device Type	1	0	0	0	0	0	1	0	1	0D

Note: 1. The AT27LV512A has the same Product Identification Code as the AT27C512R. Both are programming compatible.

AT27LV512A

Rapid Programming Algorithm

A 100 μ s CE pulse width is used to program. The address is set to the first location. V_{CC} is raised to 6.5V and OE/V_{PP} is raised to 13.0V. Each address is first programmed with one 100 μ s CE pulse without verification. Then a verification / reprogramming loop is executed for each address. In the event a byte fails to pass verification, up to 10 successive 100 μ s pulses are applied with a verification after each pulse. If the byte fails to verify after 10 pulses have been applied, the part is considered failed. After the byte verifies properly, the <u>next</u> address is selected until all have been checked. OE/V_{PP} is then lowered to V_{IL} and V_{CC} to 5.0V. All bytes are read again and compared with the original data to determine if the device passes or fails.



Ordering Information

tACC	lcc	(mA)	Ordering Code	Deekere	Operation Dance
(ns)	Active	Standby	Ordering Code	Package	Operation Range
90	8	0.02	AT27LV512A-90JC AT27LV512A-90RC AT27LV512A-90TC	32J 28R 28T	Commercial (0°C to 70°C)
	8	0.02	AT27LV512A-90JI AT27LV512A-90RI AT27LV512A-90TI	32J 28R 28T	Industrial (-40°C to 85°C)
120	8	0.02	AT27LV512A-12JC AT27LV512A-12RC AT27LV512A-12TC	32J 28R 28T	Commercial (0°C to 70°C)
	8	0.02	AT27LV512A-12JI AT27LV512A-12RI AT27LV512A-12TI	32J 28R 28T	Industrial (-40°C to 85°C)
150	8	0.02	AT27LV512A-15JC AT27LV512A-15RC AT27LV512A-15TC	32J 28R 28T	Commercial (0°C to 70°C)
	8	0.02	AT27LV512A-15JI AT27LV512A-15RI AT27LV512A-15TI	32J 28R 28T	Industrial (-40°C to 85°C)

	Package Type					
32J	32 Lead, Plastic J-Leaded Chip Carrier (PLCC)					
28R	28 Lead, 0.330" Wide, Plastic Gull Wing Small Outline (SOIC)					
28T	28 Lead, Thin Small Outline Package (TSOP)					

